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IEE CNF	IEE Conference Proceeding		ASIC, 2003. Proceeding Volume 1, 21-24 Oct. 2	2003 Page(s):229 - 2	32 Vol.1		
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		[²	Zhang; Wu-Tung Cheng Design Automation Cor	kherjee; Chien-Chur g; Reddy, S.M.; nference, 2002. Proc ernational Conferenc i:511 - 516 10.1109/ASPDAC.2 : <u>PDF</u> (413 KB) IEE	g Tsai; Samman, O.; Ya eedings of ASP-DAC 200 se on VLSI Design. Proce 002.994971	02 <u>.</u> 7th As	
		Г 3	3. Static pin mapping an Yu Huang; Wu-Tung Cl Quality Electronic Desig 24-26 March 2003 Pag Digital Object Identifier AbstractPlus Full Text Rights and Permissions	heng; Chien-Chung gn, 2003. Proceeding e(s):99 - 104 10.1109/ISQED.200 :: <u>PDF</u> (327 KB) IEE	Tsai; Mukherjee, N.; Red gs. Fourth International S 3.1194716	ldy, S.M.;	
		Г '	4. Standard automatic to frameworks, VXI instr	est system (SATS) rument front panels	hardware interface star , power module interfa	ndards fo ce, augm	r SATS entation module

5.
"ATE open system platform" IEEE-P1552 structured architecture for test systems (SATS)
Stora, M.J.; Droste, D.;
AUTOTESTCON 2003. IEEE Systems Readiness Technology Conference. Proceedings

AUTOTESTCON '98. IEEE Systems Readiness Technology Conference., 1998 IEEE

interface, receiver fixture interface, pin map configuration

Digital Object Identifier 10.1109/AUTEST.1998.713509

AbstractPlus | Full Text: PDF(972 KB) | IEEE CNF

24-27 Aug. 1998 Page(s):627 - 638

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Stora, M.J.;

22-25 Sept. 2003 Page(s):85 - 94
Digital Object Identifier 10.1109/AUTEST.2003.1243559
AbstractPlus | Full Text: PDF(976 KB) IEEE CNF
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6. IEEE-P1552 packaging architecture for computer-busboard systems (PACS)

Stora, M.J.; Droste, D.;

<u>AUTOTESTCON Proceedings, 2001. IEEE Systems Readiness Technology Conference</u> 20-23 Aug. 2001 Page(s):38 - 52

Digital Object Identifier 10.1109/AUTEST.2001.948918

AbstractPlus | Full Text: PDF(1168 KB) | IEEE CNF

Rights and Permissions

7. Receiver Fixture Interface (RFI) IEEE P1505 system standard

Stora, M.J.;

AUTOTESTCON '99. IEEE Systems Readiness Technology Conference, 1999. IEEE

30 Aug.-2 Sept. 1999 Page(s):787 - 799

Digital Object Identifier 10.1109/AUTEST.1999.800454

AbstractPlus | Full Text: PDF(828 KB) | IEEE CNF

Rights and Permissions

8. Technology insertion in a MATE station: lessons learned

Jenkins, R.; Andrews, D.;

AUTOTESTCON '92. IEEE Systems Readiness Technology Conference, Conference Record

21-24 Sept. 1992 Page(s):287 - 293

Digital Object Identifier 10.1109/AUTEST.1992.270100

AbstractPlus | Full Text: PDF(684 KB) IEEE CNF

Rights and Permissions

9. IEEE P1505 receiver fixture interface (RFI) standard

Stora, M.J.;

Autotestcon, 2005. IEEE

26-29 Sept. 2005 Page(s):596 - 613

Digital Object Identifier 10.1109/AUTEST.2005.1609205

AbstractPlus | Full Text: PDF(1716 KB) IEEE CNF

Rights and Permissions

10. Core-clustering based SoC test scheduling optimization

Yu Huang; Reddy, S.M.; Wu-Tung Cheng;

Test Symposium, 2002. (ATS '02). Proceedings of the 11th Asian

18-20 Nov. 2002 Page(s):405 - 410

Digital Object Identifier 10.1109/ATS.2002.1181745

AbstractPlus | Full Text: PDF(511 KB) | IEEE CNF

Rights and Permissions

11. Automated TPS rehost software

Winter, G.; Frank, B.;

AUTOTESTCON '99. IEEE Systems Readiness Technology Conference, 1999. IEEE

30 Aug.-2 Sept. 1999 Page(s):511 - 517

Digital Object Identifier 10.1109/AUTEST.1999.800422

AbstractPlus | Full Text: PDF(408 KB) IEEE CNF

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12. An interactive environment for the transparent logic simulation and testing of integrated

Castrodale, G.L.; Dollas, A.; Krakow, W.T.;

Test Conference, 1990. Proceedings., International

10-14 Sept. 1990 Page(s):394 - 403

Digital Object Identifier 10.1109/TEST.1990.114047

AbstractPlus | Full Text: PDF(680 KB) | IEEE CNF